Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/755,881	HSU, FU-LU	
Examiner	Art Unit	
Tan Le	3632	

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	SEAR	CHED	
Class	Subclass	Date	Examiner
rys	206.2	6/9/05	3
	205.5	1	\
	205.7		
	362		
	363		
	683		
	689		

INT	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			
ryf	205.5-	6/9/05	The			
	206.4					
	264, 363					

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Tepi Seml	6/9/07	R		
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